

Notice of References Cited	Application/Control No. 10/526,115		Applicant(s)/Patent Under Reexamination KAARIO ET AL.	
	Examiner Van Kim T. Nguyen		Art Unit 2456	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2001/0054082	12-2001	Rudolph et al.	709/217
*	C	US-7,316,347	01-2008	Poor, David Deas Sinkler	235/375
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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